Sheet 1 of 1

FORM PT (REV.7-80		)		DEPARTMENT OF				APPLICATION NO. 10/621,262		
						APPLICANTS				
	01	ENFORMATION DISCLOSURE STATEMENT				Nicolas Demange et al.				
			Use several sheets if necessary)					GROUP ART UNIT 2812		
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U.S. PATENT DOCUMENTS										
EXAMINER INITIAL			DOCUMENT NUMBER	DATE	NAME .		CLAS	S SUBCLASS	FILING DATE IF APPROPRIATE	
M		AA	5,350,705 09/27/94		Brassington et al.		257	295	` }	
AB		AB	5,418,388	05/23/95	Okudaira et al.		257	295		
	AC 5,519,237 05/21/96		Itoh et al.		257	306				
	AD 5,796,133		08/18/98	Kwon et al.		257	295	V		
	AE 5,796,136		08/18/98	Shinkawata		365	306			
		ДF	5,955,758	09/21/99	Sandhu et	al.	257	306		
		AG	6,028,361	02/22/00	Ooishi		257	774		
$\Delta$	<u>~</u>	AH	6,063,656	05/16/00	Clampitt		438	239		
		AJ							<b>√</b>	
FOREIGN PATENT DOCUMENTS										
			DOCUMENT NUMBER	<del></del>		COUNTRY			TRANSLATION YES NO	
		AJ	-	-					123 10	
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OTHER PRIOR ART (Including Author Title Date Positional Process Stall										
OTHER PRIOR ART (Including Author, Title, Date, Pertinent Pages, Etc.)										
1	Amanuma, K. et al., "Capacitor-on-Metal/Via-stacked-Plug (CMVP) Memory Cell for 0.25um CMOS Embedded Fe RAM", <i>IEEE</i> , 1998, pg. 363-366.									
	Jones, Robert E. Jr., "Integration of Ferroelectric Nonvolatile Memories." Solid State									
10	Technology, October 1997, pp. 201-210.									
		АО	Takashima, D. et al., "A Sub-40ns Random-Access Chain FRAM Architecture with a 7ns							
11.			Cell-Plate-Line Drive," IEEE International Solid-State Circuits Conference, 1999, pp. 102-							
		103.								
0		AP	Yamazaki, T., et al., "Advanced 0.5um FRAM Device Technology with Full Compatibility							
//(		of Half-Micron CMOS Logic device", Advanced Process Integration Department, Fuji								
	1		Limited. (4 pe							
EXAMINER H. Jey 756 DATE CONSIDERED										
* EXAMINER: Initial if reference considered, whether or not criteria is in conformance with MPEP 609. Draw line through citation if not in										
conformance and not considered. Include copy of this form with next communication to applicant(s).										